



IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Kazuhiro Nakajima

Serial No.: 10/649,833

Group Art Unit: 2817

Filed: August 28, 2003

Examiner: Shingleton, Michael B.

For: TEST METHOD AND APPARATUS FOR VERIFYING FABRICATION OF
TRANSISTORS IN AN INTEGRATED CIRCUIT

Honorable Commissioner of Patents
Alexandria, VA 22313-1450

AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action dated March 9, 2005, please amend the above-identified application as follows: